

**SMPS MOSFET**

**IRF7450PbF**

HEXFET® Power MOSFET

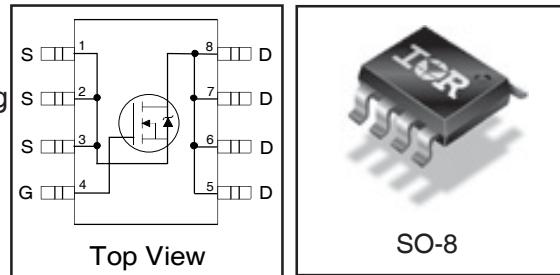
**Applications**

- High frequency DC-DC converters
- Lead-Free

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
200V	0.17Ω@V <sub>GS</sub> = 10V	2.5A

**Benefits**

- Low Gate to Drain Charge to Reduce Switching Losses
- Fully Characterized Capacitance Including Effective C<sub>OSS</sub> to Simplify Design (See App. Note AN1001)
- Fully Characterized Avalanche Voltage and Current



**Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	2.5	A
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	2.0	
I <sub>DM</sub>	Pulsed Drain Current ①	20	
P <sub>D</sub> @ T <sub>A</sub> = 25°C	Power Dissipation④	2.5	W
	Linear Derating Factor	0.02	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ⑥	11	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

**Thermal Resistance**

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJL</sub>	Junction-to-Drain Lead	—	20	°C/W
R <sub>θJA</sub>	Junction-to-Ambient ④	—	50	

Notes ① through ⑥ are on page 8

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International  
Rectifier

## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.26	—	$\text{V}^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$ ③
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.17	$\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 1.5\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	3.0	—	5.5	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{\text{DS}} = 200\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 160\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{\text{GS}} = 30\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -30\text{V}$

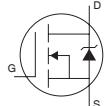
## Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

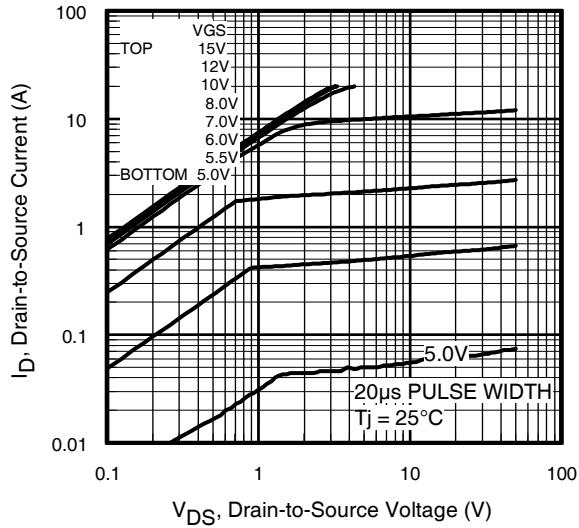
	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{\text{fs}}$	Forward Transconductance	2.6	—	—	S	$V_{\text{DS}} = 50\text{V}, I_D = 1.5\text{A}$
$Q_g$	Total Gate Charge	—	26	39	nC	$I_D = 1.5\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	6.0	9.0		$V_{\text{DS}} = 160\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	12	18	ns	$V_{\text{GS}} = 10\text{V},$
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	10	—		$V_{\text{DD}} = 100\text{V}$
$t_r$	Rise Time	—	3.0	—		$I_D = 1.5\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	17	—		$R_G = 6.0\Omega$
$t_f$	Fall Time	—	18	—	pF	$V_{\text{GS}} = 10\text{V}$ ③
$C_{\text{iss}}$	Input Capacitance	—	940	—		$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	160	—		$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	33	—		$f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	1100	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 1.0\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	66	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 160\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss eff.}}$	Effective Output Capacitance	—	25	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V to } 160\text{V}$ ③

## Avalanche Characteristics

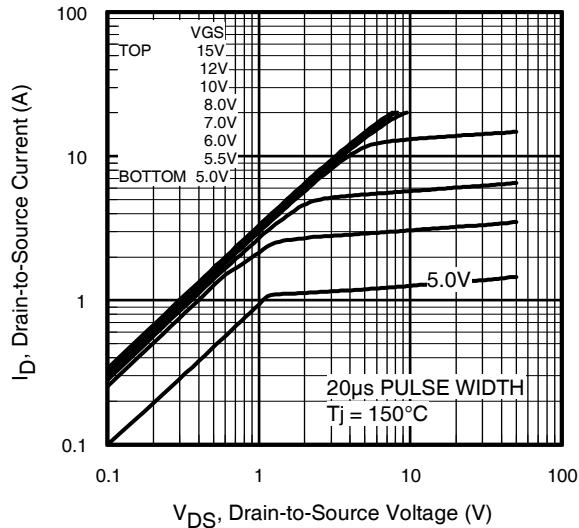
	Parameter	Typ.	Max.	Units
$E_{\text{AS}}$	Single Pulse Avalanche Energy ②	—	230	mJ
$I_{\text{AR}}$	Avalanche Current ①	—	2.5	A

## Diode Characteristics

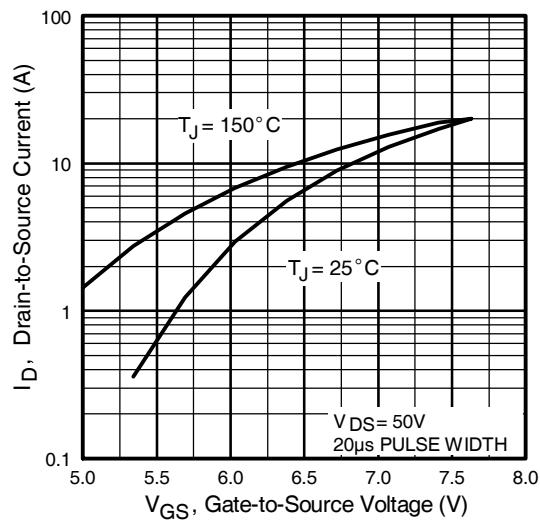
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	2.3	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	20		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 1.5\text{A}, V_{\text{GS}} = 0\text{V}$ ③
$t_{\text{rr}}$	Reverse Recovery Time	—	97	146	ns	$T_J = 25^\circ\text{C}, I_F = 1.5\text{A}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	350	525	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③



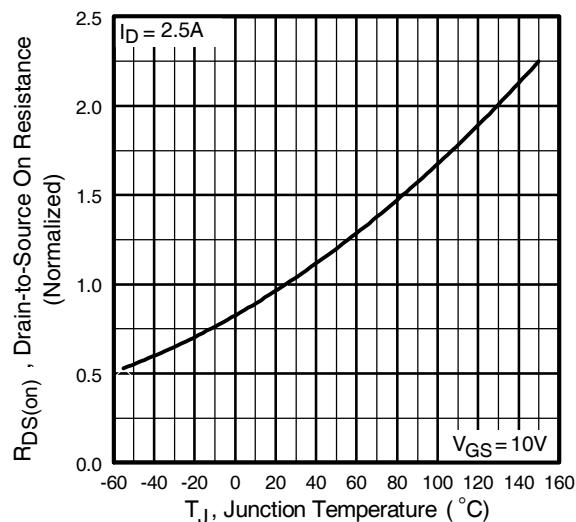
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



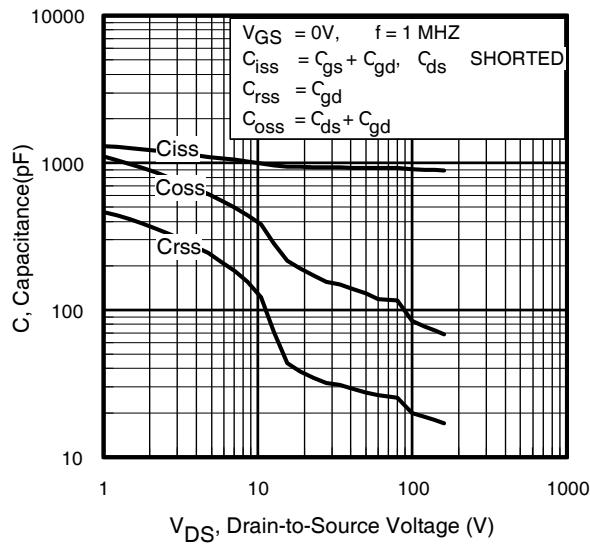
**Fig 3.** Typical Transfer Characteristics



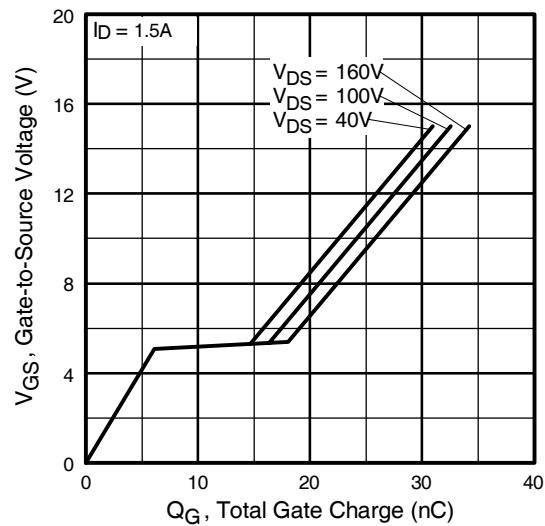
**Fig 4.** Normalized On-Resistance Vs. Temperature

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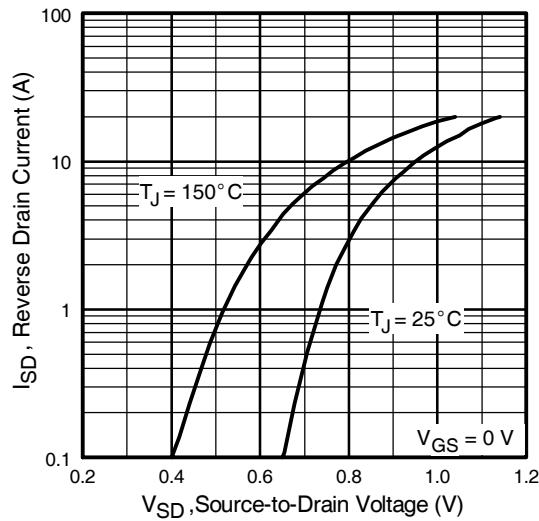
International  
**IR** Rectifier



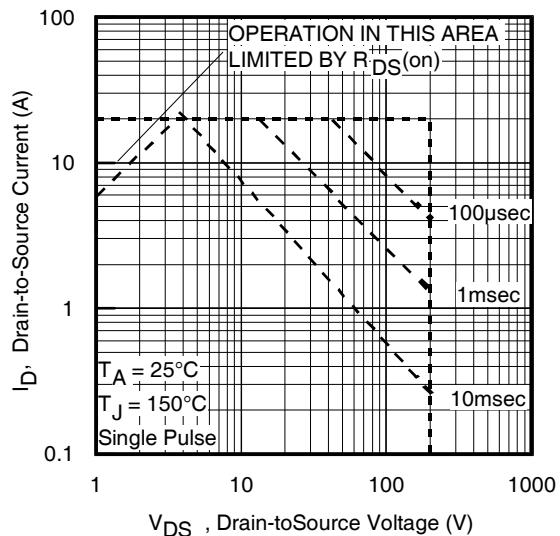
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



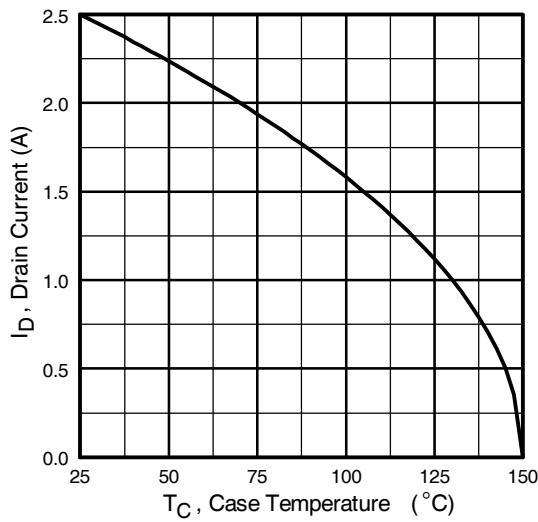
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



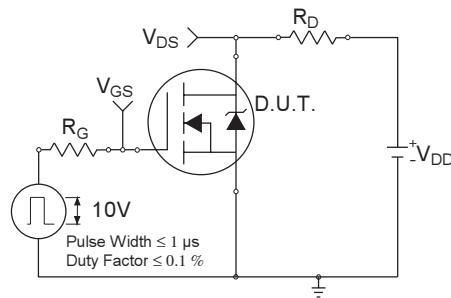
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



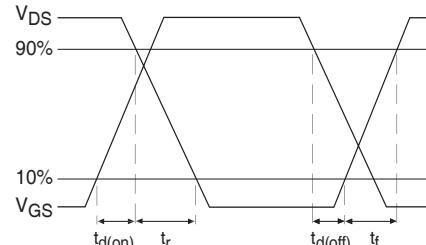
**Fig 8.** Maximum Safe Operating Area



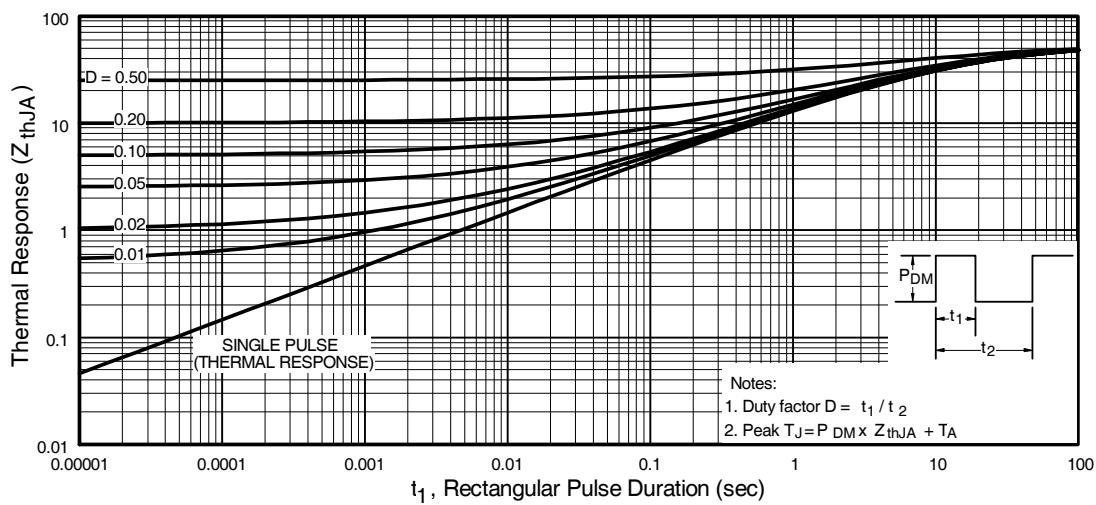
**Fig 9.** Maximum Drain Current Vs.  
Ambient Temperature



**Fig 10a.** Switching Time Test Circuit



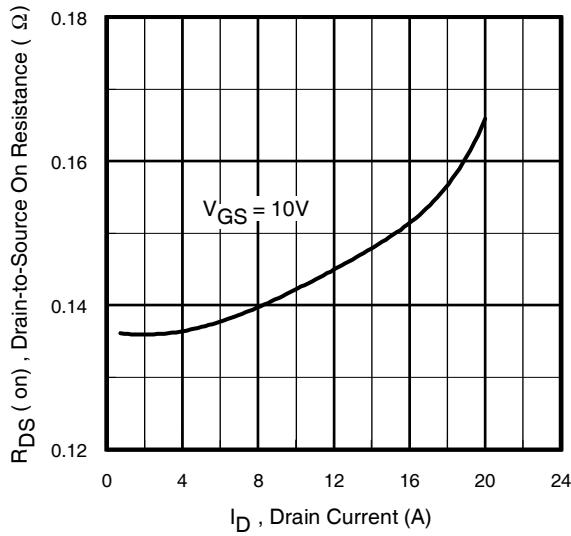
**Fig 10b.** Switching Time Waveforms



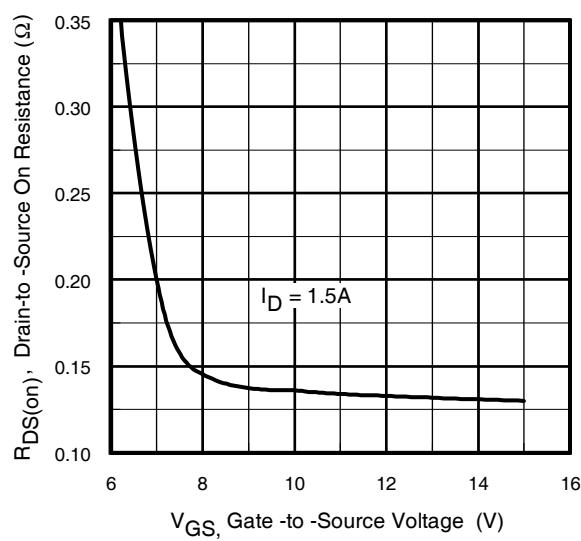
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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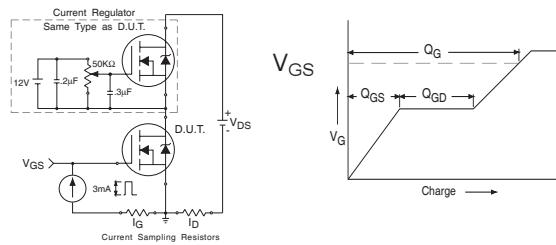
International  
Rectifier



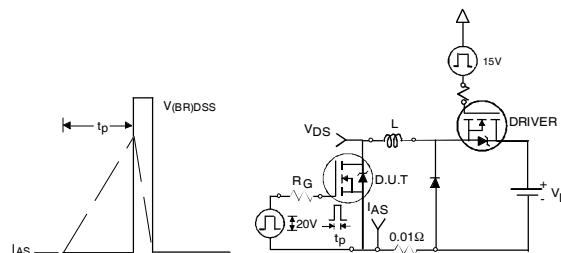
**Fig 12.** On-Resistance Vs. Drain Current



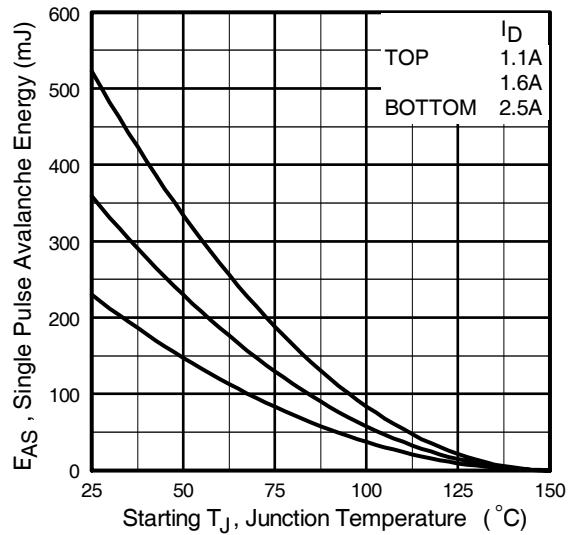
**Fig 13.** On-Resistance Vs. Gate Voltage



**Fig 14a&b.** Basic Gate Charge Test Circuit and Waveform



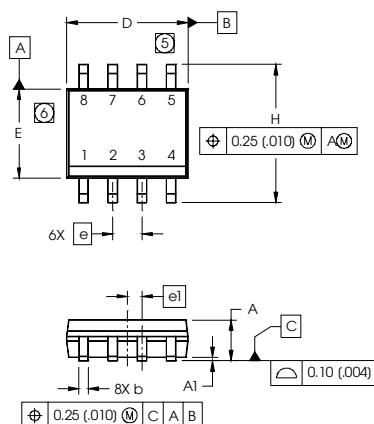
**Fig 15a&b.** Unclamped Inductive Test circuit and Waveforms



**Fig 15c.** Maximum Avalanche Energy Vs. Drain Current

## SO-8 Package Outline

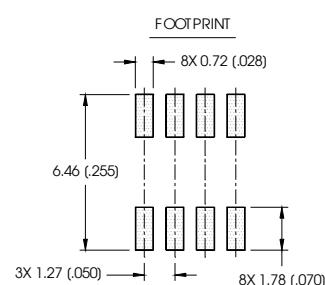
Dimensions are shown in millimeters (inches)



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.060	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
Y	0°	8°	0°	8°

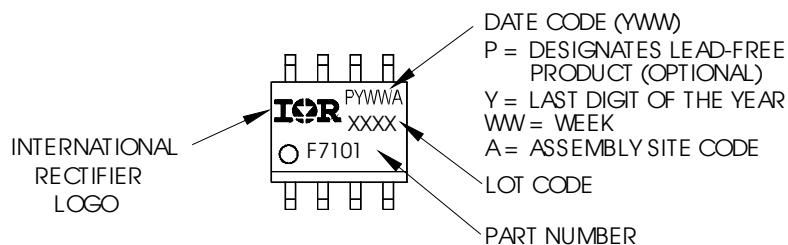
NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.  
MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.  
MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO  
A SUBSTRATE.



## SO-8 Part Marking Information (Lead-Free)

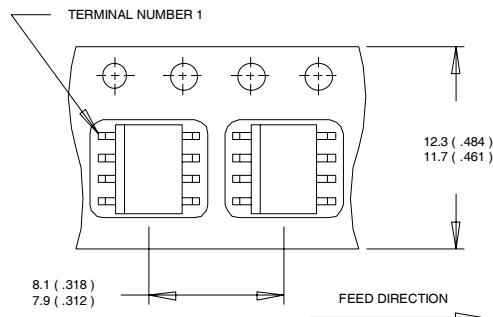
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



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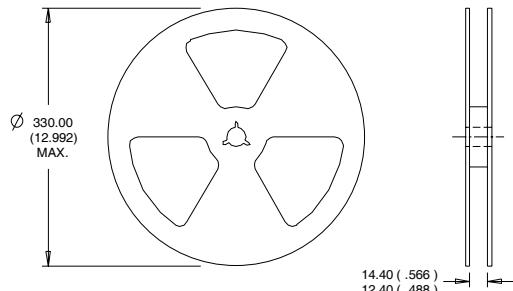
## SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

**Notes:**

- |  |   |
|--|---|
| ① Repetitive rating; pulse width limited by max. junction temperature.                                 | ③ Pulse width $\leq$ 400 $\mu$ s; duty cycle $\leq$ 2%. |
| ② Starting $T_J = 25^\circ\text{C}$ , $L = 73\text{mH}$<br>$R_G = 25\Omega$ , $I_{AS} = 2.5\text{A}$ . | ④ When mounted on 1 inch square copper board            |

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Consumer market.  
Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

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